

Notice of References Cited	Application/Control No. 10/017,164	Applicant(s)/Patent Under Reexamination KEITEL ET AL.	
	Examiner Chriss S. Yoder, III	Art Unit 2612	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-5,373,319 A	12-1994	Lee, Nam Su	348/143
	B	US-6,891,978 B1	05-2005	Takano, Manji	382/284
	C	US-6,498,564 B2	12-2002	Oda, Naoki	340/567
	D	US-5,347,431 A	09-1994	Blackwell et al.	362/11
	E	US-5,457,325 A	10-1995	Huberty, Stephane	250/559.29
	F	US-6,762,794 B1	07-2004	Ogino, Shigeru	348/262
	G	US-6,483,536 B2	11-2002	Aoyama, Chiaki	348/139
	H	US-6,878,924 B2	04-2005	Baron, John M.	250/221
	I	US-6,441,888 B1	08-2002	Azuma et al.	356/4.01
	J	US-4,081,214	03-1978	Van Buskirk, Lyman F.	356/3.03
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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